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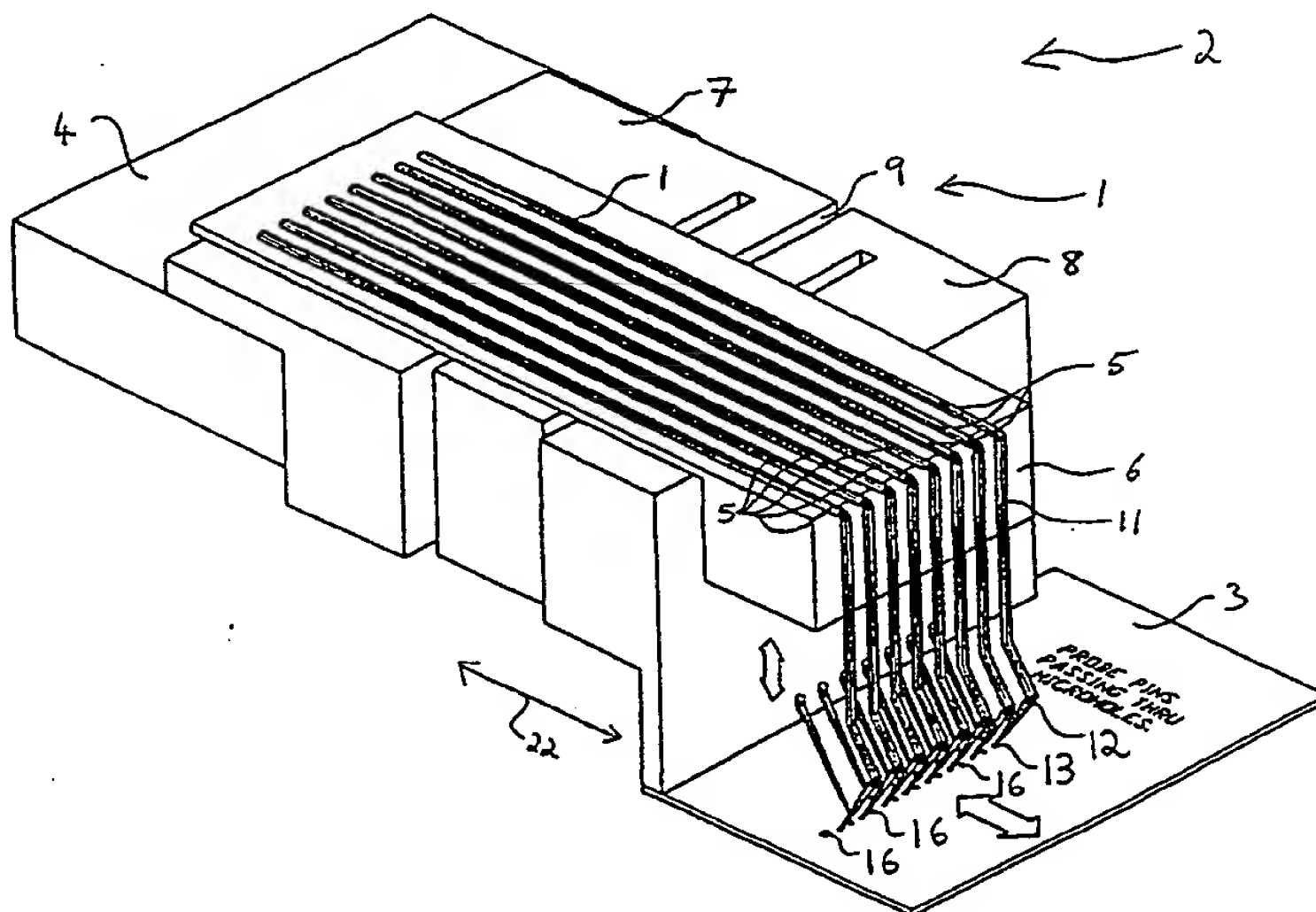
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(21) International Application Number: PCT/SG98/00068 (22) International Filing Date: 9 September 1998 (09.09.98) (71) Applicant (for all designated States except US): SPIRE TECHNOLOGIES PTE LTD. [SG/SG]; 21, Kallang Avenue #06-169/171, Singapore 339412 (SG). (72) Inventors; and (75) Inventors/Applicants (for US only): SAWHILL, Robert, Arthur, Jr. [US/SG]; 2 Hillview Way, Singapore 669173 (SG). SHAH, Paren, Indravadan [IN/SG]; 10 Rose Lane #01-01, Singapore 429076 (SG). (74) Agent: MCCALLUM, Graeme, David; Lloyd Wise, Tanjong Pagar, P.O. Box 636, Singapore 910816 (SG).		(81) Designated States: AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, CA, CH, CN, CU, CZ, DE, DK, EE, ES, FI, GB, GE, GH, GM, HR, HU, ID, IL, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MD, MG, MK, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TR, TT, UA, UG, US, UZ, VN, YU, ZW, ARIPO patent (GH, GM, KE, LS, MW, SD, SZ, UG, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GW, ML, MR, NE, SN, TD, TG). Published With international search report.

(54) Title: INTERFACE DEVICE BETWEEN TESTING EQUIPMENT AND INTEGRATED CIRCUIT



(57) Abstract

An interface device (2) provides an interface between testing equipment and an integrated circuit to be tested. The interface device (2) includes a body member (7) and a movable member (8) mounted on the body member (7) for movement with respect to the body member (7). A number of elongate contact members (5) are mounted on the movable member (8) for movement with the movable member (8). Each contact member (5) includes a contact end (10), adapted to contact a bond pad of the integrated circuit to be tested, and a body portion (11). The central axis of the body portion (11) and the contact end (10) are substantially parallel to each other.